Test Org.*	Device	Function	Technology	Mfr.	Effective SEU LET* Threshold	Device Xsection (cm^2)	Bits Tested	Bit Xsection (cm^2)	Test Date	LUth	LU Xsection (cm^2)	Fac.	Remarks 23-Aug-99
		EDAC											
	Note: Entries in **RED** indicate data added since the 1997 Compendium.												
IBM	---	32-bit	CMOS	AMD	5	1.0E-04				25	5.0E-04	BNL	
MMS	54LS630	16-bit parallel	Bipolar-LSTTL	TIX	7	1.0E-04			1992	>32			
MMS	54LS630	32-bit	Bipolar-LSTTL	TIX	7	1.0E-03				>32		GANIL	Dufour, 92IEEE Wrkshp Rec., pg. 21.
MMS	54LS670	3-state 4 x 4 Register File	Bipolar-LSTTL	SGN	5	6.0E-04							
ARSP	54LS670	3-state 4 x 4 Register File	Bipolar-LSTTL	SGN	5	6.0E-04	3700			>75		UCB	
IBM	IDT49C460	32-bit	CMOS	IDT	17					25	2.0E-03	BNL	No SEU cross section @ LET=40 due to LU.
ARSP	IDT49C460	32-bit	CMOS	IDT	>100	1.0E-07			May-91	>100		UCB	
GSFC	IDT49C460	32-bit	CMOS	IDT	15 to 20	5.0E-05			Nov-94	>80		BNL	LaBel. Cross section for all five error types monitored.
ARSP	IDT49C460	32-bit	CMOS	IDT	>100	1.0E-07			Jan-91	>100		UCB	

Legend

Manufacturers: AMD - Advanced Micro Devices; IDT - Integrated Device Technology; SGN - Signetics Corp; TIX - Texas Instruments

Test Organizations

ARSP - Aerospace Corp., El Segundo, CA

GSFC - Goddard Space Flight Center, Greenbelt, MD

IBM - IBM Federal Systems Division, Manassas, VA

MMS - Matra Marconi Space, France

Radiation Test Facilities

BNL - Tandem Van de Graaff, Brookhaven National Laboratories, Long Island, NY

GANIL - GANIL Accelerator, France

UCB - 88-inch Cyclotron, University of California, Berkeley, CA